

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/538,825	YE, CHUN
	<b>Examiner</b> Derek S. Chapel	<b>Art Unit</b> 2872

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>